SGS-THOMSON MICROELECTRONICS

N - CHANNEL ENHANCEMENT MODE POWER MOS TRANSISTORS

TYPE	V_{DSS}	$R_{DS(on)}$	I_D
MTH40N06	60 V	0.028 Ω	40 A
MTH40N06FI	60 V	0.028 Ω	26 A

- VERY LOW ON-LOSSES
- RATED FOR UNCLAMPED INDUCTIVE SWITCHING (ENERGY TEST) ♦
- LOW DRIVE ENERGY FOR EASY DRIVE
- HIGH TRANSCONDUCTANCE/C_{rss} RATIO

AUTOMOTIVE POWER APPLICATIONS

N - channel enhancement mode POWER MOS field effect transistors. Easy drive and very fast switching times make these POWER MOS transistors ideal for high speed switching circuit in applications such as power actuator driving, motor drive including brushless motors, hydraulic actuators and many other uses in automotive applications.
They also find use in DC/DC converters and uninterruptible power supplies.

TO-218   ISOWATT218

INTERNAL SCHEMATIC DIAGRAM
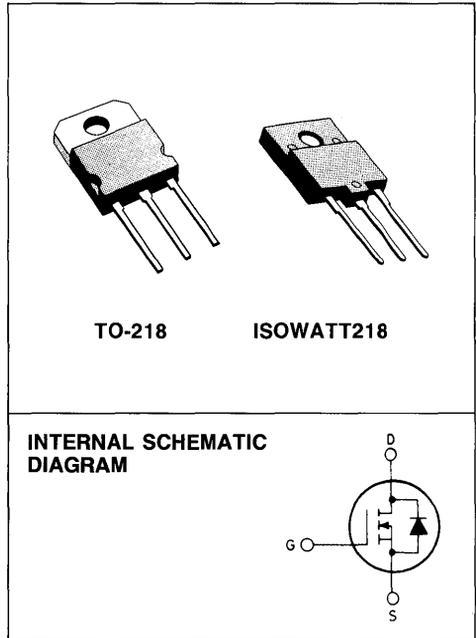
ABSOLUTE MAXIMUM RATINGS

		TO-218 ISOWATT218	MTH40N06 MTH40N06FI	
V_{DS}	Drain-source voltage ($V_{GS} = 0$)		60	V
V_{DGR}	Drain-gate voltage ($R_{GS} = 1$ MΩ)		60	V
V_{GS}	Gate-source voltage		±20	V
I_{DM}	Drain current (pulsed)		140	A
		TO-218	ISOWATT218	
I_D ■	Drain current (cont.) $T_c = 20°C$	40	26	A
P_{tot} ■	Total dissipation at $T_c < 25°C$	150	65	W
■	Derating factor	1.2	0.52	W/°C
T_{stg}	Storage temperature		− 65 to 150	°C
T_j	Max. operating junction temperature		150	°C

■ See note on ISOWATT218 in this datasheet
♦ Introduced in 1988 week 44

THERMAL DATA ∎

			TO-218	ISOWATT218	
$R_{thj - case}$	Thermal resistance junction-case	max	0.83	1.92	°C/W
T_l	Maximum lead temperature for soldering purpose	max	275		°C

ELECTRICAL CHARACTERISTICS ($T_{case} = 25$°C unless otherwise specified)

Parameters		Test Conditions	Min.	Typ.	Max.	Unit
OFF						
$V_{(BR) DSS}$	Drain-source breakdown voltage	$I_D = 100 \ \mu A$ $\qquad V_{GS} = 0$	60			V
I_{DSS}	Zero gate voltage drain current ($V_{GS} = 0$)	$V_{DS} =$ Max Rating $\times$ 0.85 $V_{DS} =$ Max Rating $\times$ 0.85 $T_c = 100$°C			250 1000	μA μA
I_{GSS}	Gate-body leakage current ($V_{DS} = 0$)	$V_{GS} = \pm 20$ V			± 100	nA
ON *						
$V_{GS (th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$ $\quad I_D = 1$ mA $V_{DS} = V_{GS}$ $\quad I_D = 1$ mA $T_c = 100$°C	2 1.5		4.5 4	V V
$R_{DS (on)}$	Static drain-source on resistance	$V_{GS} = 10$ V $\quad I_D = 20$ A			0.028	Ω
$V_{DS (on)}$	Drain-source on voltage	$V_{GS} = 10$ V $\quad I_D = 40$ A $V_{GS} = 10$ V $\quad I_D = 20$ A $T_c = 100$°C			1.4 1.12	V V
ENERGY TEST						
I_{UIS}	Unclamped inductive switching current (single pulse)	$V_{DD} = 30$ V $\qquad L = 100 \ \mu H$ starting $T_j = 25$°C	40			A
DYNAMIC						
g_{fs} *	Forward transconductance	$V_{DS} = 15$ V $\quad I_D = 20$ A	10			mho
C_{iss} C_{oss} C_{rss}	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25$ V $\qquad f = 1$ MHz $V_{GS} = 0$			5000 2500 1000	pF pF pF
Q_g	Total gate charge	$V_{DS} = 50$ V $\quad I_D = 40$ A $V_{GS} = 10$ V			120	nC

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ELECTRICAL CHARACTERISTICS (Continued)

Parameters		Test Conditions		Min.	Typ.	Max.	Unit

SWITCHING

$t_{d\ (on)}$	Turn-on time	$V_{DD} = 25$ V	$I_D = 20$ A			50	ns
t_r	Rise time	$R_{gen} = 50\ \Omega$				300	ns
$t_{d\ (off)}$	Turn-off delay time					150	ns
t_f	Fall time					100	ns

SOURCE DRAIN DIODE

V_{SD}	Forward on voltage	$I_{SD} = 40$ A	$V_{GS} = 0$			3	V
t_{rr}	Reverse recovery time	$I_{SD} = 40$ A	$V_{GS} = 0$		200		ns
t_{on}	Forward turn-on time				150		ns

* Pulsed: Pulse duration $\leqslant$ 300 μs, duty cycle $\leqslant$ 2%
■ See note on ISOWATT218 in this datasheet

Safe operating areas
(standard package)

Thermal impedance
(standard package)

Derating curve
(standard package)
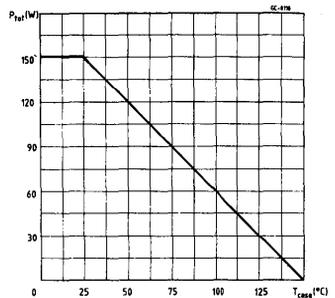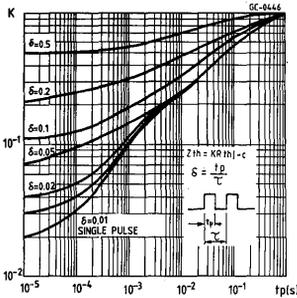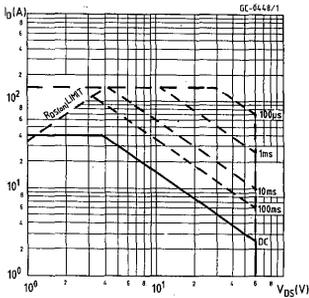
Output characteristics

Output characteristics

Transfer characteristics
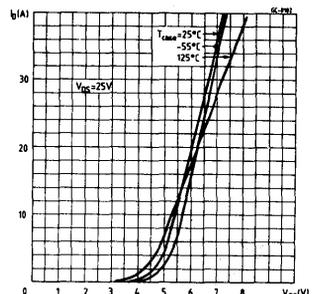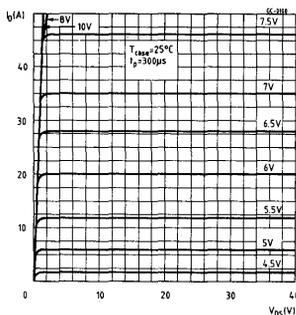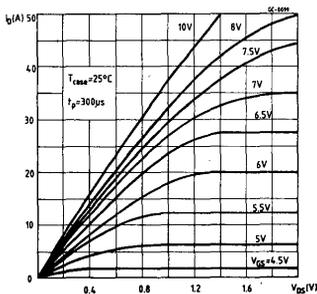
Transconductance
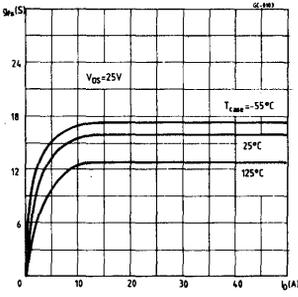

Static drain-source on resistance
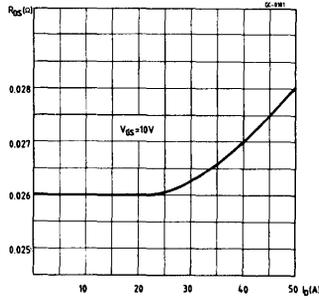
Gate charge vs gate-source voltage
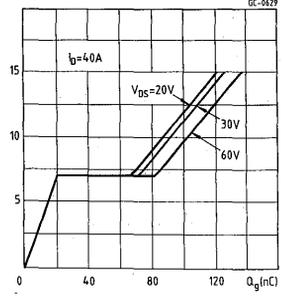
Capacitance variation
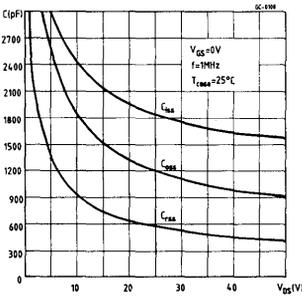
Normalized gate threshold voltage vs temperature
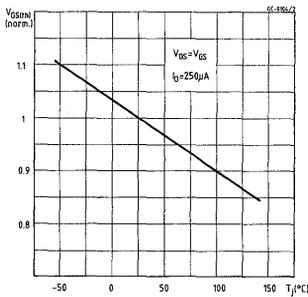

Normalized breakdown voltage vs temperature
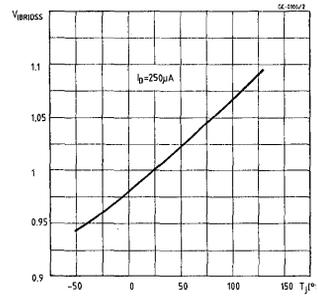
Normalized on resistance vs temperature
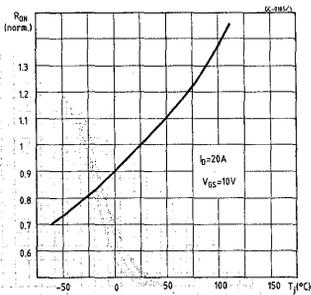

Source-drain diode forward characteristics

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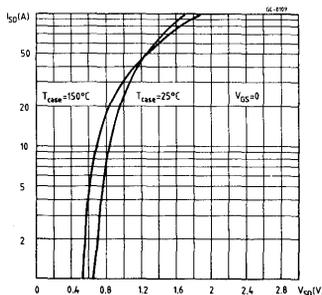
Switching times test circuit for resistive load

Switching time waveforms for resistive load
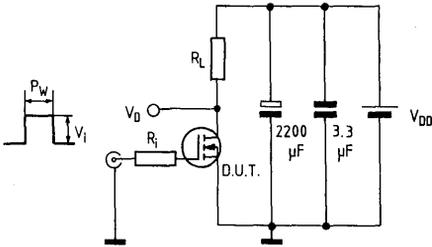
Pulse width $\leqslant$ 100 μs
Duty cycle $\leqslant$ 2%

SC-0008/1
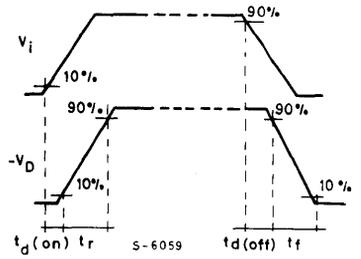
Unclamped inductive load test circuit

Unclamped inductive waveforms
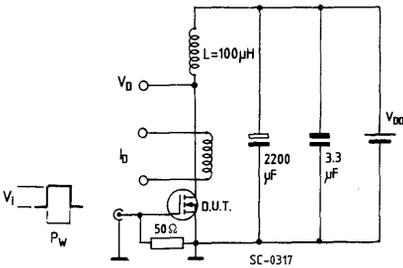
V_i = 12 V - Pulse width: adjusted to obtain specified I_{DM}

SC-0317

SC-0316
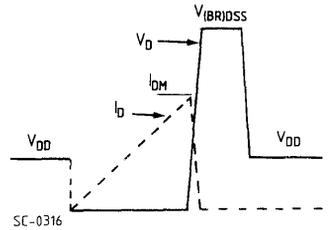
Gate charge test circuit

Body-drain diode t_{rr} measurement Jedec test circuit
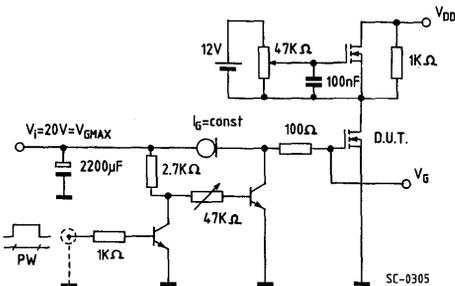
PW adjusted to obtain required V_G

SC-0305
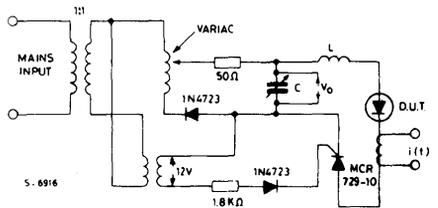
ISOWATT218 PACKAGE CHARACTERISTICS AND APPLICATION.

ISOWATT218 is fully isolated to 4000V dc. Its thermal impedance, given in the data sheet, is optimised to give efficient thermal conduction together with excellent electrical isolation.

The structure of the case ensures optimum distances between the pins and heatsink. These distances are in agreement with VDE and UL creepage and clearance standards. The ISOWATT218 package eliminates the need for external isolation so reducing fixing hardware.

The package is supplied with leads longer than the standard TO-218 to allow easy mounting on pcbs. Accurate moulding techniques used in manufacture assures consistent heat spreader-to-heatsink capacitance

ISOWATT218 thermal performance is better than that of the standard part, mounted with a 0.1mm mica washer. The thermally conductive plastic has a higher breakdown rating and is less fragile than mica or plastic sheets. Power derating for ISOWATT218 packages is determined by:

$$P_D = \frac{T_j - T_c}{R_{th}}$$

from this I_{Dmax} for the POWER MOS can be calculated:

$$I_{Dmax} \leqslant \sqrt{\frac{P_D}{R_{DS(on) \, (at \, 150°C)}}}$$

THERMAL IMPEDANCE OF ISOWATT218 PACKAGE

Fig. 1 illustrates the elements contributing to the thermal resistance of transistor heatsink assembly, using ISOWATT218 package.

The total thermal resistance $R_{th \, (tot)}$ is the sum of each of these elements.

The transient thermal impedance, Z_{th} for different pulse durations can be estimated as follows:

1 - for a short duration power pulse less than 1ms;

$$Z_{th} < R_{thJ-C}$$

2 - for an intermediate power pulse of 5ms to 50ms:

$$Z_{th} = R_{thJ-C}$$

3 - for long power pulses of the order of 500ms or greater:

$$Z_{th} = R_{thJ-C} + R_{thC-HS} + R_{thHS-amb}$$

It is often possibile to discern these areas on transient thermal impedance curves.

Fig. 1
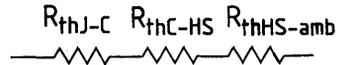
ISOWATT DATA

Safe operating areas
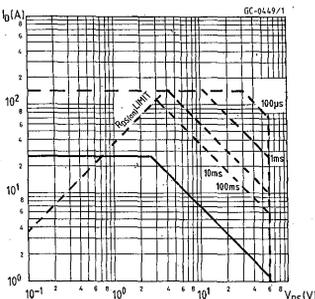
Thermal impedance

Derating curve

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